Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/772,167	GONYE ET AL.	
Examiner	Art Unit	
Mark L. Shibuya, Ph.D.	1639	

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Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
·	DATE	EXMR	
VEST, term, inventor search			
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